

<b>Notice of References Cited</b>	Application/Control No. 10/521,703		Applicant(s)/Patent Under Reexamination KUIJPER ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0031954 A1	02-2003	Kakuta et al.	430/270.2
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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